

AUTOMOTIVE GRADE

AUIRLR014N

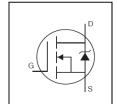
HEXFET® Power MOSFET

Features

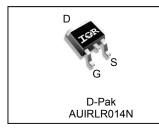
- Advanced Planar Technology
- · Logic Level Gate Drive
- Low On-Resistance
- Dynamic dV/dT Rating
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated
- · Repetitive Avalanche Allowed up to Timax
- · Lead-Free, RoHS Compliant
- Automotive Qualified *

Description

Specifically designed for Automotive applications, this cellular design of HEXFET® Power MOSFETs utilizes the latest processing techniques to achieve low on-resistance per silicon area. This benefit combined with the fast switching speed and ruggedized device design that HEXFET power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in Automotive and a wide variety of other applications.



V _{DSS}		55V
R _{DS(on)}	max.	0.14Ω
I _D		10A



G	D	S
Gate	Drain	Source

Page part number	Dookogo Typo	Standard Pack	\$	Orderable Part Number	
Base part number		Form	Quantity	Orderable Part Number	
AUIRLR014N	D Dak	Tube	75	AUIRLR014N	
AUIKLKU 14IN	D-Pak	Tape and Reel Left	3000	AUIRLR014NTRL	

Absolute Maximum Ratings

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (TA) is 25°C, unless otherwise specified.

Symbol	Symbol Parameter		Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V	10	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V	7.1	Α
I _{DM}	Pulsed Drain Current ①	40	
$P_D @ T_C = 25^{\circ}C$	Maximum Power Dissipation	28	W
	Linear Derating Factor	0.2	W/°C
V_{GS}	Gate-to-Source Voltage	± 16	V
E _{AS}	Single Pulse Avalanche Energy (Thermally Limited) ②	35	mJ
I _{AR}	Avalanche Current ①	6.0	A
E _{AR}	Repetitive Avalanche Energy ①	2.8	mJ
dv/dt	Peak Diode Recovery®	5.0	V/ns
TJ	Operating Junction and	-55 to + 175	
T_{STG}	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	

Thermal Resistance

Symbol	Symbol Parameter		Max.	Units
$R_{\theta JC}$	Junction-to-Case ©		5.3	
$R_{ heta JA}$	Junction-to-Ambient (PCB Mount) ∅		50	°C/W
$R_{\theta JA}$	Junction-to-Ambient		110	

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^{*}Qualification standards can be found at www.infineon.com



Static @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	55			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.056		V/°C	Reference to 25°C, I _D = 1mA
R _{DS(on)}	Static Drain to Source On Begintance			0.14		V _{GS} = 10V, I _D = 6.0A ④
	Static Drain-to-Source On-Resistance			0.21	Ω	$V_{GS} = 4.5V, I_D = 5.0A$ @
$V_{GS(th)}$	Gate Threshold Voltage	1.0		3.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
gfs	Forward Trans conductance	3.1			S	$V_{DS} = 25V, I_{D} = 6.0A$
ı	Drain-to-Source Leakage Current			25	μA	$V_{DS} = 55V, V_{GS} = 0V$
IDSS	Drain-to-Source Leakage Current			250	μΑ	$V_{DS} = 55V, V_{GS} = 0V, T_{J} = 150^{\circ}C$
I _{GSS}	Gate-to-Source Forward Leakage			100	nA	V _{GS} = 16V
	Gate-to-Source Reverse Leakage			-100	IIA	V _{GS} = - 16V

Dynamic Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

Total Gate Charge			7.9		$I_D = 6.0A$
Gate-to-Source Charge			1.4	nC	V _{DS} = 44V
Gate-to-Drain Charge			4.4		V _{GS} = 5.0V, See Fig. 6 &13 ④
Turn-On Delay Time		6.5			$V_{DD} = 28V$
Rise Time		47		no	$I_{D} = 6.0A$
Turn-Off Delay Time		12		115	$R_G = 6.2\Omega, V_{GS} = 5.0V$
Fall Time		23			$R_D = 4.5\Omega$, See Fig. 104
Internal Drain Inductance		4.5			Between lead, 6mm (0.25in.)
Internal Source Inductance		7.5			from package and center of die contact
Input Capacitance		265			$V_{GS} = 0V$
Output Capacitance		80		pF	$V_{DS} = 25V$
Reverse Transfer Capacitance		38			f = 1.0MHz, See Fig.5
	Gate-to-Source Charge Gate-to-Drain Charge Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Internal Drain Inductance Internal Source Inductance Input Capacitance Output Capacitance	Gate-to-Source Charge —— Gate-to-Drain Charge —— Turn-On Delay Time —— Rise Time —— Turn-Off Delay Time —— Fall Time —— Internal Drain Inductance —— Internal Source Inductance —— Input Capacitance —— Output Capacitance ——	Gate-to-Source Charge — — Gate-to-Drain Charge — — Turn-On Delay Time — 6.5 Rise Time — 47 Turn-Off Delay Time — 12 Fall Time — 23 Internal Drain Inductance — 4.5 Internal Source Inductance — 7.5 Input Capacitance — 265 Output Capacitance — 80	Gate-to-Source Charge — 1.4 Gate-to-Drain Charge — 4.4 Turn-On Delay Time — 6.5 — Rise Time — 47 — Turn-Off Delay Time — 12 — Fall Time — 23 — Internal Drain Inductance — 4.5 — Internal Source Inductance — 7.5 — Input Capacitance — 265 — Output Capacitance — 80 —	Gate-to-Source Charge — — 1.4 nC Gate-to-Drain Charge — 4.4 Turn-On Delay Time — 6.5 — Rise Time — 47 — Turn-Off Delay Time — 12 — Fall Time — 23 — Internal Drain Inductance — 4.5 — Internal Source Inductance — 7.5 — Input Capacitance — 265 — Output Capacitance — 80 — pF

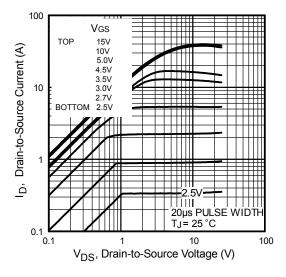
Diode Characteristics

	71040 0114140101101100					
	Parameter	Min.	Тур.	Max.	Units	Conditions
ı	Continuous Source Current			10		MOSFET symbol
Is	(Body Diode)			10	_	showing the
ı	Pulsed Source Current			40	A	integral reverse
ISM	(Body Diode) ①			- 40		p-n junction diode.
V_{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C, I_S = 6.0A, V_{GS} = 0V $
t _{rr}	Reverse Recovery Time		37	56	ns	$T_J = 25^{\circ}C$, $I_F = 6.0A$
Q_{rr}	Reverse Recovery Charge		48	71	nC	di/dt = 100A/µs④
t _{on}	Forward Turn-On Time	Intrinsio	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)			

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- ② Starting $T_J = 25^{\circ}C$, L = 1.96mH, $R_G = 25\Omega$, $I_{AS} = 6A$ (See fig. 12)
- $\label{eq:local_state} \begin{tabular}{ll} \begin{tabular}{ll}$
- 4 Pulse width $\leq 300 \mu s$; duty cycle $\leq 2\%$.
- S This is applied for I-PAK, Ls of D-PAK is measured between lead and center of die contact.
- When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994





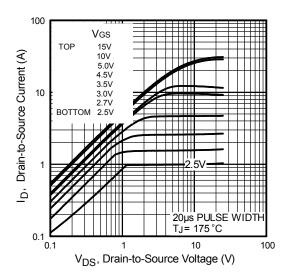
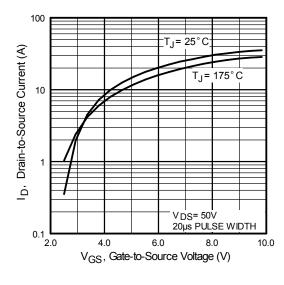


Fig. 1 Typical Output Characteristics

Fig. 2 Typical Output Characteristics





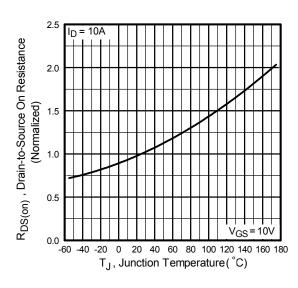


Fig. 4 Normalized On-Resistance Vs. Temperature



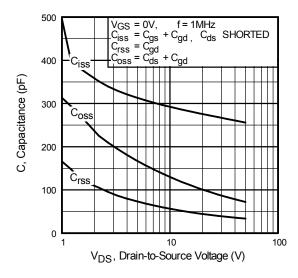


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

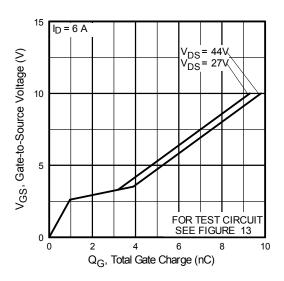


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage

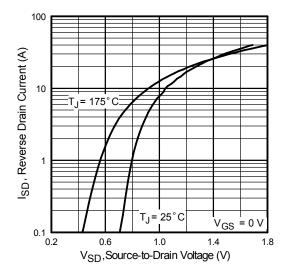


Fig. 7 Typical Source-to-Drain Diode Forward Voltage

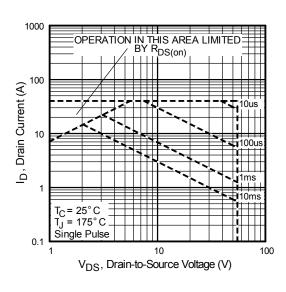


Fig 8. Maximum Safe Operating Area

4



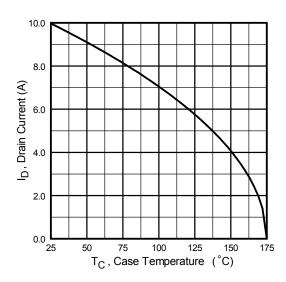


Fig 9. Maximum Drain Current Vs. Case Temperature

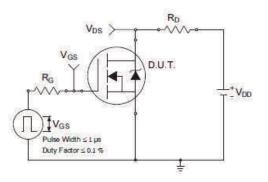


Fig 10a. Switching Time Test Circuit

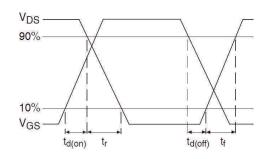


Fig 10b. Switching Time Waveforms

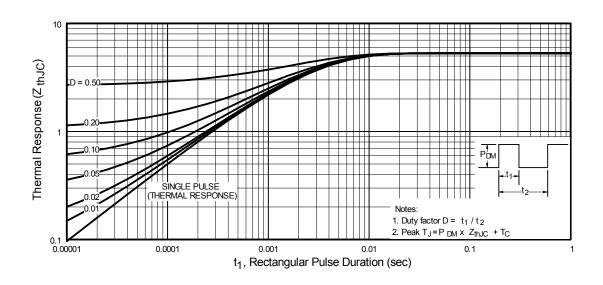


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case



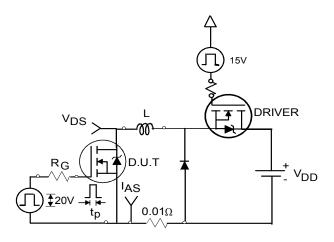


Fig 12a. Unclamped Inductive Test Circuit

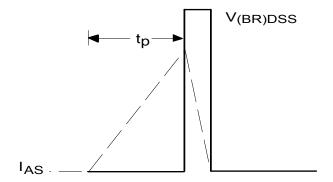


Fig 12b. Unclamped Inductive Waveforms

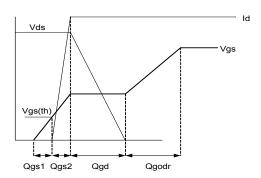


Fig 13a. Gate Charge Waveform

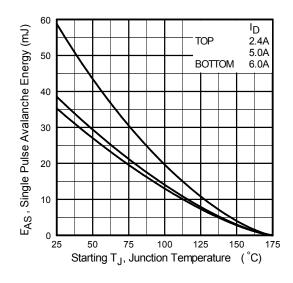


Fig 12c. Maximum Avalanche Energy vs. Drain Current

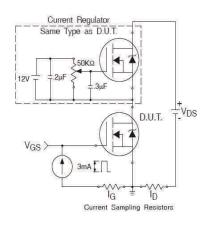
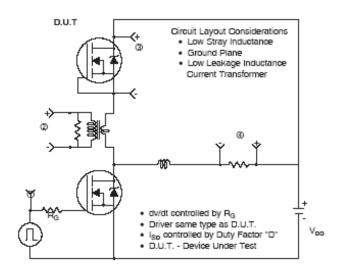
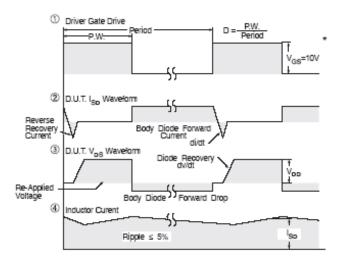


Fig 13b. Gate Charge Test Circuit



Peak Diode Recovery dv/dt Test Circuit





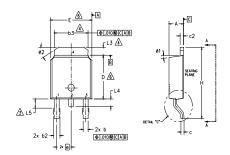
^{*} V_{GS} = 5V for Logic Level Devices

Fig 14. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

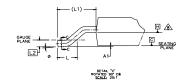
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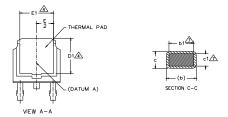


D-Pak (TO-252AA) Package Outline (Dimensions are shown in millimeters (inches))









NOTES:

- 1.- DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2.- DIMENSION ARE SHOWN IN INCHES [MILLIMETERS].
- LEAD DIMENSION UNCONTROLLED IN L5.
- A- DIMENSION D1, E1, L3 & b3 ESTABLISH A MINIMUM MOUNTING SURFACE FOR THERMAL PAD.
- 5.— SECTION C-C DIMENSIONS APPLY TO THE FLAT SECTION OF THE LEAD BETWEEN .005 AND 0.10 [0.13 AND 0.25] FROM THE LEAD TIP.
- Limension D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005 [0.13] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
- A- DIMENSION b1 & c1 APPLIED TO BASE METAL ONLY.
- ♠ DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 9.- OUTLINE CONFORMS TO JEDEC OUTLINE TO-252AA.

S Y M	DIMENSIONS					
B	MILLIM	ETERS	INC	HES	O T E S	
L	MIN.	MAX.	MIN.	MAX.	S	
Α	2.18	2.39	.086	.094		
A1	-	0.13	-	.005		
b	0.64	0.89	.025	.035		
ь1	0.65	0.79	.025	.031	7	
b2	0.76	1.14	.030	.045		
b3	4.95	5.46	.195	.215	4	
С	0.46	0.61	.018	.024		
c1	0.41	0.56	.016	.022	7	
c2	0.46	0.89	.018	.035		
D	5.97	6.22	.235	.245	6	
D1	5.21	-	.205	-	4	
Ε	6.35	6.73	.250	.265	6	
E1	4.32	-	.170	-	4	
е	2.29	BSC	.090	BSC		
Н	9.40	10.41	.370	.410		
L	1.40	1.78	.055	.070		
L1	2.74	BSC	.108	REF.		
L2	0.51	BSC	.020	BSC		
L3	0.89	1.27	.035	.050	4	
L4	-	1.02	-	.040		
L5	1.14	1.52	.045	.060	3	
ø	0,	10°	0,	10°		
ø1	0,	15*	0,	15*		
ø2	25*	35°	25*	35°		

LEAD ASSIGNMENTS

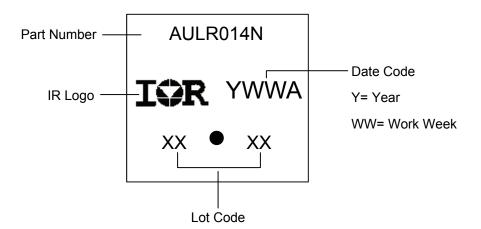
HEXFET

- 1.- GATE
- 2.- DRAIN
- 3.- SOURCE 4.- DRAIN

IGBT & CoPAK

- 1.- GATE
- 2.- COLLECTOR 3.- EMITTER
- 4. COLLECTOR

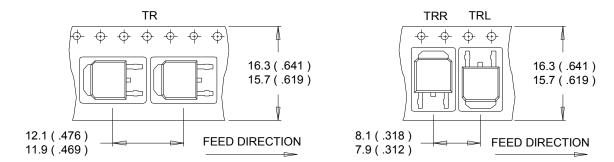
D-Pak (TO-252AA) Part Marking Information



Note: For the most current drawing please refer to IR website at http://www.irf.com/package/

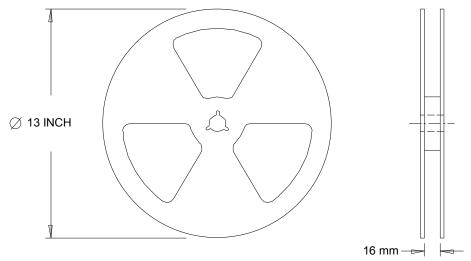


D-Pak (TO-252AA) Tape & Reel Information (Dimensions are shown in millimeters (inches))



NOTES:

- 1. CONTROLLING DIMENSION: MILLIMETER.
- 2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
- 3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES:

1. OUTLINE CONFORMS TO EIA-481.

Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



Qualification Information

		1					
		Automotive					
		(per AEC-Q101)					
		Comments: This part number(s) passed Automotive qualification. Infineon's Industrial and Consumer qualification level is granted by extension of the higher Automotive level.					
Moisture Sensitivity Level D-Pak			MSL1				
			Class M1B (+/- 75V) [†]				
	Machine Model	AEC-Q101-002					
FOD	Lluman Dady Madal	Class H1A (+/- 300V) †					
ESD	Human Body Model	AEC-Q101-001					
	Channed Davis Madel	Class C5 (+/- 2000V) [†]					
Charged Device Model		AEC-Q101-005					
RoHS Compliant		Yes					

[†] Highest passing voltage.

Revision History

Date	Comments			
12/11/2015	Updated datasheet with corporate template			
12/11/2015	Corrected ordering table on page 1.			

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